

In re Patent Application of:  
**VAIL ET AL.**  
Serial No. 09/991,559  
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**In the Specification:**

Please amend paragraph 0033 on page 10 of the originally filed specification as follows:

Furthermore, when respective charging/discharging times are measured through the high and low calibration resistors **28**, **29**, these charging/discharging times may be used to determine circuit error parameters such as variability of the capacitor **20** (i.e., capacitance variation) and changes in the input logic threshold of the Schmitt hysteresis input device **27**. While the temperature may be calculated using only the charging/discharging time through the circuit element **21**, using the calibration resistors **28**, **29** provides for even greater accuracy because the charging/discharging time may then be substantially normalized to changes in the thermistor resistance alone. The temperature measurement accuracy thus achieved may therefore approach the accuracy of the circuit element **21** alone, which for a thermistor may be  $\pm 0.1^{\circ}\text{C}$  or better.